

<b>Notice of References Cited</b>	Application/Control No. 09/590,897		Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner JAMES M. MITCHELL		Art Unit 2813	Page 1 of 1

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IBM Technical disclosure, "Module Probe Package", 5/1991, Vol. 33 Issue 12 pages 85-86
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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